Applicant(s)/Patent Under Application/Control No. Reexamination 09/888,717 HEIN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Sam K. Ahn 2637 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 327/115 US-6,229,357 B1 05-2001 Nair et al. Α US-В US-С US-D US-Ε F US-US-G US-Η US-1 US-US-K US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U V W Х

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